

# Automotive Qualification Results Summary for ADuM3210W/ADuM3211W Die Revision and Data Sheet Change

QUALIFICATION PLAN / STATUS			
TEST	SPECIFICATION	SAMPLE SIZE	RESULTS
High Temperature Operating Life (HTOL)*	JEDEC <i>JESD22-A108</i>	9x77	Pass
Highly Accelerated Stress Test (HAST)*	JEDEC <i>JESD22-A110</i>	9x77	Pass
Temperature Cycle (TC)*	JEDEC <i>JESD22-A104</i>	4x77 4x45	Pass
Autoclave (AC)*	JEDEC <i>JESD22-A102</i>	5x77 4x45	Pass
High Temperature Storage Life (HTSL)	JEDEC <i>JESD22-A103</i>	2x77 5x45	Pass
Solder Heat Resistance (SHR)*	JEDEC/IPC <i>J-STD-020</i>	1x30	Pass
Latch-Up	JEDEC <i>JESD78</i>	1x9	Pass ±150mA @ +8.25V
Electrostatic Discharge <i>Human Body Model</i>	ESDA/JEDEC <i>JS-001</i>	1x18	Pass ±4000V
Electrostatic Discharge <i>Field-Induced Charged Device Model</i>	JEDEC <i>JESD22-C101</i>	1x18	Pass ±1250V

\* Pre- and post-stress electrical test was performed at room and hot temperatures.

These samples were subjected to preconditioning (per J-STD-020 Level 3) prior to the start of the stress test. Level 3 preconditioning consists of the following: Bake: 24 hrs @ 125°C, Unbiased Soak: 192 hrs @ 30°C, 60%RH, Reflow: 3 passes through an oven with a peak temperature of 260°C.